

Notice of Allowability

Application No.

10/092,442

Applicant(s)

AKIYAMA ET AL.

Examiner

Michael P. Stafira

Art Unit

2877



-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to amendment filed 5/17/2004.
2. ☒ The allowed claim(s) is/are 1-16.
3. ☒ The drawings filed on 08 March 2002 are accepted by the Examiner.
4. ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☒ All b) ☐ Some* c) ☐ None of the:
 1. ☒ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

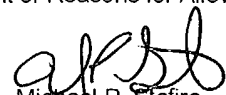
Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.

THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

5. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
 6. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.
- Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
7. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. ☐ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date _____
4. ☐ Examiner's Comment Regarding Requirement for Deposit
of Biological Material
5. ☐ Notice of Informal Patent Application (PTO-152)
6. ☐ Interview Summary (PTO-413),
Paper No./Mail Date _____
7. ☐ Examiner's Amendment/Comment
8. ☒ Examiner's Statement of Reasons for Allowance
9. ☐ Other _____


Michael P. Stafira
Primary Examiner
Art Unit: 2877

DETAILED ACTION

Priority

1. Receipt is acknowledged of papers submitted under 35 U.S.C. 119(a)-(d), which papers have been placed of record in the file.

Allowable Subject Matter

2. Claims 1-16 are allowed over the prior art of record.
3. The following is an examiner's statement of reasons for allowance:

Regarding claim 1, the prior art fails to disclose or make obvious a method for measuring light transmittance of a lens undergoing examination having the step of supply a light of a predetermined wavelength narrowed along an optical axis and a step of focusing the light to converge along the optical axis when the lens undergoing examination is not disposed on the optical axis and measuring the intensity of the light to generate a baseline value then determining the light transmittance of the lens undergoing examination from the lens transmission value and the baseline value, and in combination with the other recited limitations of claim 1. Claims 2-6 are allowed by the virtue of dependency on the allowed claim 1.

Regarding claim 7, the prior art fails to disclose or make obvious an apparatus for measuring light transmittance of a lens undergoing examination having a the microprocessor electronically connected to receive a lens transmission value from the first light detector when the lens is disposed in the first lens holding apparatus and a baseline transmission from the first light detector value when no lens is disposed in the first lens holding apparatus and the microprocessor is further disposed to calculate a ratio of the lens transmission value and the baseline transmission value and the send the ratio to one or more elements selected from the

group consisting of a display element and a memory unit, and in combination with the other recited limitations of claim 7. Claims 8-13 are allowed by the virtue of dependency on the allowed claim 7.

Regarding claim 14, the prior art fails to disclose or make obvious an apparatus for measuring light transmittance having a second light source emitting light of a predetermined second wavelength, wherein the second light source is disposed on a second optical axis and the predetermined second wavelength is different from the predetermined first wavelength; a second light detector for detecting the light of the predetermined second wavelength, wherein the second light detector is disposed on the second optical axis and generates output signals in response to detecting light of the predetermined second wavelength, and wherein the first lens holding apparatus is disposed between the second light source and the second light detector and is positioned on the second optical axis; a second lens holding apparatus for holding the lens undergoing examination when the first lens holding apparatus is not holding the lens undergoing examination, wherein the second lens holding apparatus is disposed between the second light source and the second light detector and is positioned on the second optical axis, wherein the second lens holder releasably holds the lens undergoing examination; an additional first convergence lens for converging rays of the light of the predetermined second wavelength at a second prescribed position, wherein the second prescribed position is on or near the lens undergoing examination when the second lens holding apparatus is holding the lens undergoing examination, an additional second convergence lens disposed between the second lens holding apparatus and the second light detector, wherein the additional second convergence lens serves to converge rays of the light of the second predetermined wavelength into the second light detector;

and a second interference filter disposed along the second optical axis and on a path of the rays of the light of the predetermined second wavelength, wherein the second interference filter transmits mostly light having a wavelength within a range about the predetermined second wavelength, wherein the microprocessor receives signals from the first light detector of the first sub-apparatus and receives signals from the second light detector of the second sub-apparatus, and the microprocessor determines the light transmittance of the lens undergoing examination based upon the signals received from the first light detector and the second light detector, and in combination with the other recited limitations of claim 14.

Regarding claim 15, the prior art fails to disclose or make obvious an apparatus for measuring light transmittance having a second light source emitting light of a predetermined second wavelength, wherein the second light source is disposed on a second optical axis and the predetermined second wavelength is different from the predetermined first wavelength; a second light detector for detecting the light of the predetermined second wavelength, wherein the second light detector is disposed on the second optical axis and generates output signals in response to detecting light of the predetermined second wavelength, and wherein the first lens holding apparatus is disposed between the second light source and the second light detector and is positioned on the second optical axis; a second lens holding apparatus for holding the lens undergoing examination when the first lens holding apparatus is not holding the lens undergoing examination, wherein the second lens holding apparatus is disposed between the second light source and the second light detector and is positioned on the second optical axis, wherein the second lens holder releasably holds the lens undergoing examination; an additional first convergence lens for converging rays of the light of the predetermined second wavelength at a

second prescribed position, wherein the second prescribed position is on or near the lens undergoing examination when the second lens holding apparatus is holding the lens undergoing examination, an additional second convergence lens disposed between the second lens holding apparatus and the second light detector, wherein the additional second convergence lens serves to converge rays of the light of the second predetermined wavelength into the second light detector; and a second interference filter disposed along the second optical axis and on a path of the rays of the light of the predetermined second wavelength, wherein the second interference filter transmits mostly light having a wavelength within a range about the predetermined second wavelength, wherein the microprocessor receives signals from the first light detector of the first sub-apparatus and receives signals from the second light detector of the second sub-apparatus, and the microprocessor determines the light transmittance of the lens undergoing examination based upon the signals received from the first light detector and the second light detector, and in combination with the other recited limitations of claim 15.

Regarding claim 16, the prior art fails to disclose or make obvious an apparatus for measuring light transmittance having a second light source emitting light of a predetermined second wavelength, wherein the second light source is disposed on a second optical axis and the predetermined second wavelength is different from the predetermined first wavelength; a second light detector for detecting the light of the predetermined second wavelength, wherein the second light detector is disposed on the second optical axis and generates output signals in response to detecting light of the predetermined second wavelength, and wherein the first lens holding apparatus is disposed between the second light source and the second light detector and is positioned on the second optical axis; a second lens holding apparatus for holding the lens

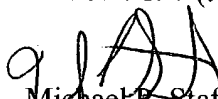
undergoing examination when the first lens holding apparatus is not holding the lens undergoing examination, wherein the second lens holding apparatus is disposed between the second light source and the second light detector and is positioned on the second optical axis, wherein the second lens holder releasably holds the lens undergoing examination; an additional first convergence lens for converging rays of the light of the predetermined second wavelength at a second prescribed position, wherein the second prescribed position is on or near the lens undergoing examination when the second lens holding apparatus is holding the lens undergoing examination, an additional second convergence lens disposed between the second lens holding apparatus and the second light detector, wherein the additional second convergence lens serves to converge rays of the light of the second predetermined wavelength into the second light detector; and a second interference filter disposed along the second optical axis and on a path of the rays of the light of the predetermined second wavelength, wherein the second interference filter transmits mostly light having a wavelength within a range about the predetermined second wavelength, wherein the microprocessor receives signals from the first light detector of the first sub-apparatus and receives signals from the second light detector of the second sub-apparatus, and the microprocessor determines the light transmittance of the lens undergoing examination based upon the signals received from the first light detector and the second light detector, and in combination with the other recited limitations of claim 16.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Michael P. Stafira whose telephone number is 571-272-2430. The examiner can normally be reached on 4/10 Schedule Mon.-Thurs..

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Frank Font can be reached on 571-272-2415. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).


Michael P. Stafira
Primary Examiner
Art Unit 2877

July 6, 2004